

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 09/881,870 | Applicant(s)/Patent Under Reexamination LI ET AL. | |
| | Examiner Andrew C. Lee | Art Unit 2664 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-5,600,630 | 02-1997 | Takano et al. | 370/218 |
| | B | US-6,600,741 | 07-2003 | Chrin et al. | 370/375 |
| | C | US-6,493,347 | 12-2002 | Sindhu et al. | 370/401 |
| | D | US-6,850,524 | 02-2005 | Troxel et al. | 370/395.32 |
| | E | US-5,353,283 | 10-1994 | Tsuchiya, Paul F. | 370/392 |
| | F | US-6,553,031 | 04-2003 | Nakamura et al. | 370/392 |
| | G | US-6,798,777 | 09-2004 | Ferguson et al. | 370/392 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.